

Form PTO 1449 U.S. Department of Commerce Patent and Trademark Office Information Disclosure Statement by Applicant	ATTY. DOCKET NUMBER	SERIAL NUMBER
	HITA.0437	To be assigned
	APPLICANT	
	HIGETA et al.	
	FILING DATE	GROUP
	Concurrently herewith	2824

U.S. Patent Documents

Examiner Initial		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
ap	*	5,677,889	10/14/97	Haraguchi et al.	365	226	8/18/95
ap	*	2001/0006476 A1	7/5/2001	Itoh et al.	365	156	2/23/2001
ap	*	2002/0027256 A1	3/7/2002	Ishibashi et al	257	391	11/16/01
ap	*	6,046,627	4/4/2000	Itoh et al	327	546	2/20/98
ap	*	5,757,702	5/26/98	Iwata et al	365	189.05	10/29/96
ap	X	6,316,812	11/13/01	Nagaoka	257	369	05/04/00
ap	X	5,875,133	02/23/99	Miyashita et al	365	189.09	07/19/96

Foreign Patent Documents

Examiner Initial		DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	No
ap	*	5-120882	10/29/91	Japan			Abstract	X
ap	*	58-161195	3/19/82	Japan			Abstract	X
ap	*	2-295164	5/10/89	Japan			Abstract	X
ap	*	8-69693	8/30/94	Japan				X
ap	*	9-51042	2/15/96	Japan				X
ap	*	2001-15704		Japan				X
ap	*	WO 97/38444	4/8/97	PCT			Abstract	X
ap	*	10-242839	2/28/97	Japan				X
ap	*	3-83289	8/25/89	Japan			Abstract	X

Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)

ap	*	Takakuni Douseki and Shin-ichiro Mutoh, "Static-Noise Margin Analysis for a Scaled-Down CMOS Memory Cell", Journal of Institute of Electronics Information and Communication Engineers C-11, (July 1992), Vol. J75-c-11 No. 7, pp. 350-361
ap	*	T. Inukai, M. Takamiya, K. Nose, H. Kawaguchi, T. Hiramoto and T. Sakurai, "Boosted Gate MOS (BGMOS): Device/Circuit Cooperation Scheme to Achieve Leakage-Free Giga-Scale Integration", IEEE 2000 Custom Integrated Circuits Conference, pp. 409-412
EXAMINER <i>Chris Fleming</i>		DATE CONSIDERED <i>5/4/04</i>
<p>* Filed by Applicant in parent X Cited by Examiner in Parent Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant</p>		